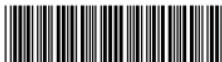


<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10573166	TANAKA ET AL.
Examiner	Art Unit	
Sheela J Huff	1643	

### SEARCHED

Class	Subclass	Date	Examiner

### SEARCH NOTES

Search Notes	Date	Examiner
inventor serach on PALNM	10/21/08	sjh
SCORE- SEQ ID NO. 2 and 3	10/21/08	sjh
Stic structure search	10/21/08	sjh
WEST-insert	10/21/08	sjh
STN-inseret	10/21/08	sjh

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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